	Application/Control No.	Applicant(s	Applicant(s)/Patent under Reexamination	ion
Issue Classification		MCGRATH ET AL.	ET AL.	
	Examiner	Art Unit		
	Li, Aimee J	2183		
ORIG	ORIGINAL	INTERNATION	INTERNATIONAL CLASSIFICATION	Z
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED	VIMED
712	229	G 0 6 F 9 /30		
CROSS REF	CROSS REFERENCE(S)	Γ		
CLASS SUBCLASS (C	SUBCLASS (ONE SUBCLASS PER BLOCK)			
712 43				
Awal M. S. (Date (8/1/2006 EDDIE CHAN EDDIE CHAN ENTER	EXAMINER	Total Claims Allowed:	Allowed:
Kegal Instruments Examiner) (Date	SUPERVISORITY TAILOR 2100 **TECHNOLOGY CENTER 2100 (Bate) (Primary Examiner)	TER 2100 Sec (Date) 8/3/0 6	O.G. Print Claim(s) 1	O.G. Print Figure 1

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